



EDP 2004

Impact of Signal Integrity on System-On-Chip Design Methodologies

Juan-Antonio Carballo

IBM Research

jantonio@us.ibm.com

VSIA IMP co-Chair

Raminderpal Singh

IBM Systems and Technology

raminder@us.ibm.com

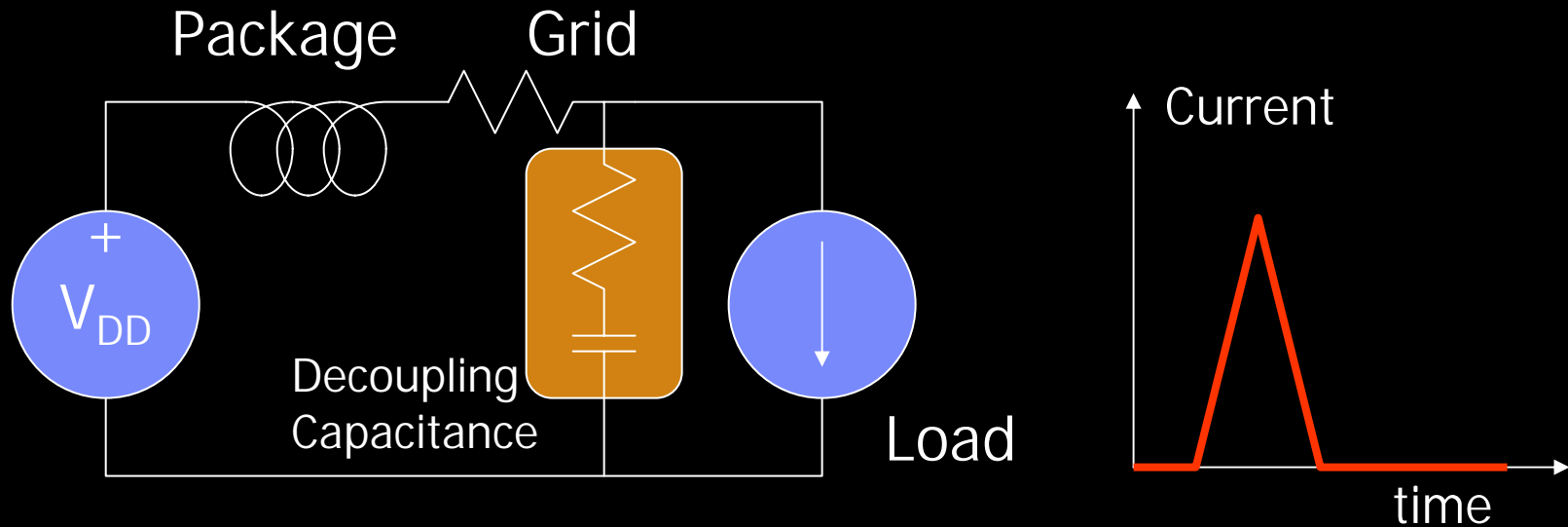
VSIA IMP co-Chair

April 2004

Introduction

- **Signal integrity**
First-order concern in System-on-a-Chip (SoC) design
- **SoC methodologies need to be fundamentally transformed**
Must develop techniques to enhance block reuse while accounting for signal integrity
- **Reuse standards work can help achieve this goal**
Virtual Socket Interface Alliance (VSIA) → focus on reuse
Signal Integrity (SI) sub-working group → focus on SI in SoC
Work integrates with SoC methodologies and enhances block reuse

Example → Power Grid Issues



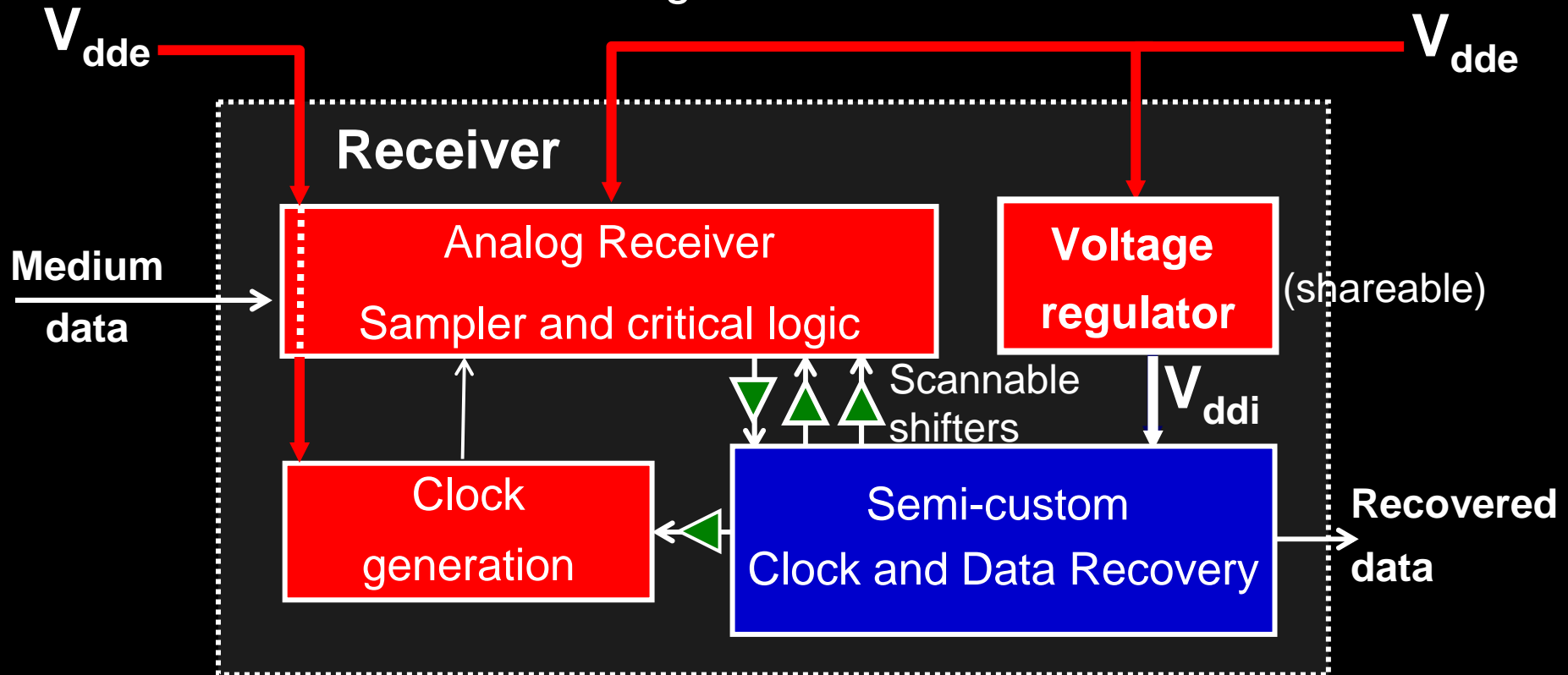
- With package, maximum noise becomes:

$$V_{\max} \approx \underbrace{\mu t_p R_g}_{DC} + \underbrace{\mu L}_{Package} - \underbrace{\mu R_g^2 C_d (1 - e^{-t_p/\tau})}_{Decap}$$

Example → Power Grid Issues Semi-custom Voltage Islands

- Reduce power, low overhead, better supply

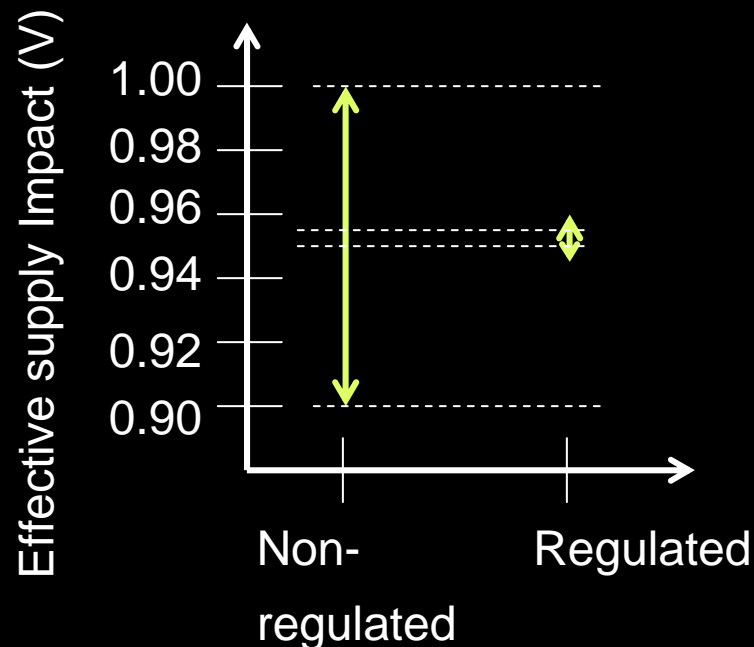
But other IP integration issues



Example → Power Grid Issues *Reduced Impact of Supply Variation*

- **Effective supply variation reduced**

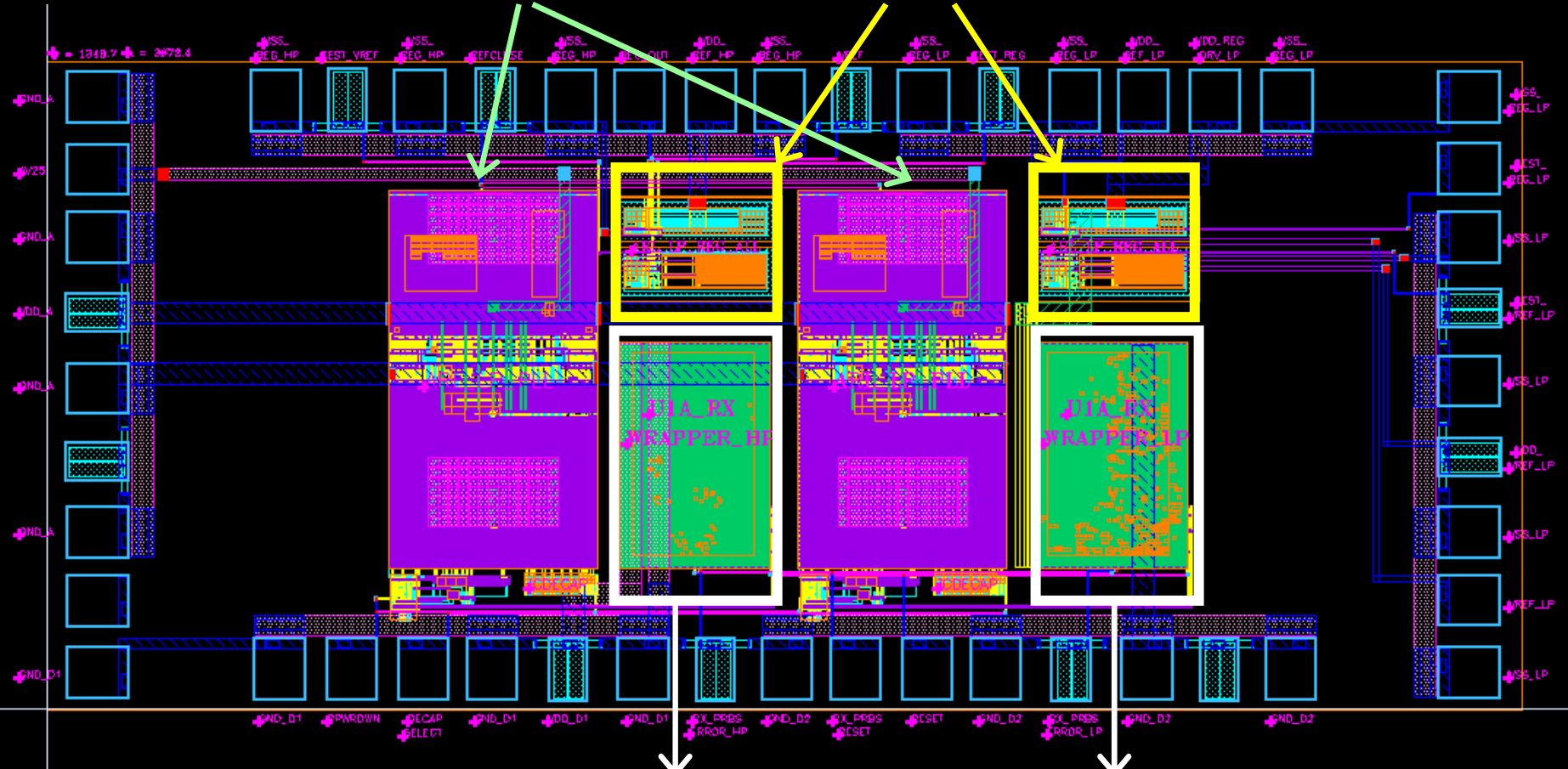
But need to account for regulator-logic / inter-island interaction...



Example → Power Grid Issues: Test Chip

PLL

Vref & Regulator



High power logic

Low power logic

VSIA Signal Integrity Sub-DWG

- **Part of Implementation DWG**

 - Implementation-verification, AMS, SI

- **Scope**

 - Digital and analog blocks

 - Signal integrity issues

 - Power grids, X-talk, substrate coupling, electromigration

- **Goals**

 - Facilitate “exchange” of digital & analog blocks in SoCs

 - Improve author-integrator communication of SI issues

- **Assumptions**

 - The blocks are provided for integration as hard blocks

Focus

- **Interconnect crosstalk**
- **Signal Electromigration**
- **Supply and ground grid noise and electromigration**
- **Substrate coupling**

Format

- **Deliverables**

Include detailed tables
Aid with implementation

- **Guidelines**

Textual advice

11.1.1.	Maximum possible number of TIC nodes meeting architectural-aggregate metrics (Area and Min circuit node size of any node TIC)	0001	004		01 available, otherwise Presence in Section 14
11.1.2.	Maximum area possible of input ports (Area of input ports only, area TIC)	0002	004		01 available, otherwise Presence in Section 14
11.1.3.	Physical dimensions for input ports (Area only, TIC)				
11.1.3.1.	0002a) Area of input ports	0002a	004	0	
11.1.3.2.	0002b) Dimensions of input ports	0002b	004	0	
11.1.3.3.	0002c) Area of input ports	0002c	004	0	
11.1.3.4.	0002d) Dimensions of input ports	0002d	004	0	
11.1.4.	Area of input ports (Area of input ports only, TIC)	0003	004		01 available, otherwise Presence in Section 14
11.1.5.	Area of input ports (Area of input ports only, TIC)	0004	004		01 available, otherwise Presence in Section 14
11.1.6.	Area of input ports (Area of input ports only, TIC)	0005	004		01 available, otherwise Presence in Section 14
11.1.7.	Area of input ports (Area of input ports only, TIC)	0006	004		01 available, otherwise Presence in Section 14
11.1.8.	Area of input ports (Area of input ports only, TIC)	0007	004		01 available, otherwise Presence in Section 14
11.2.	Physicals				
11.2.1.	Location of input ports (Area of input ports only, TIC)	0008	004		
11.2.2.	Location of output ports (Area of output ports only, TIC)	0009	004		
11.2.3.	Location of input/output ports (Area of input/output ports only, TIC)	0010	004		
11.2.4.	Area of input/output ports (Area of input/output ports only, TIC)	0011	004		
11.2.5.	"Cell" refers to TIC node (quantity identified by name)	0012	004		
11.3.	Timing				
11.3.1.	Number of timing arcs within TIC node (area of node)	0013	004		01 available, otherwise Presence in Section 14
11.3.2.	Timing arcs within input ports	0014	004		
11.3.3.	Timing arcs within output ports	0015	004		
11.3.4.	Timing arcs within input/output ports	0016	004		

Example Table Entry

- **Interconnect Crosstalk (Voltage Noise and Delay Variance)**
Electrical data

Number	Description	Format	Mandatory?	Comments
2.1.2.1.	Maximum permissible noise propagating into input ports	VC Hspice	Conditionally	If available, otherwise document in Section 2.4

Team

- **Main participants (*not* TSMC)**

 - Motorola

 - IBM

 - Simplex

 - Intel

 - Startups (e.g. CommLSI)

 - Japan

Interconnect Crosstalk (Voltage Noise and Delay Variance)

Electrical data	Physical data
Maximum noise at ports Max crosstalk for sensitive nets	Location of sensitive polygons
Electrical characteristics for aggressors and sensitive nets	Location of strong potential aggressors or No-fly zones
Best, worst case slews at ports Max load/RC at ports	Location of top-layer/peripheral supply wires “Safe” regions for OTH signals (possibly classified by slew)

Signal Electromigration

Logical data	Physical data
Mutex/One-hot relationships required between signals	Layout
Electrical data	Timing data
Current density limits, metal/via Max load on ports Max slew rate on inputs Max Switching factor Drive Strength	Variation of timing arcs within VC with external crosstalk Transition windows at ports Transition windows for potential aggressors or sensitive nets

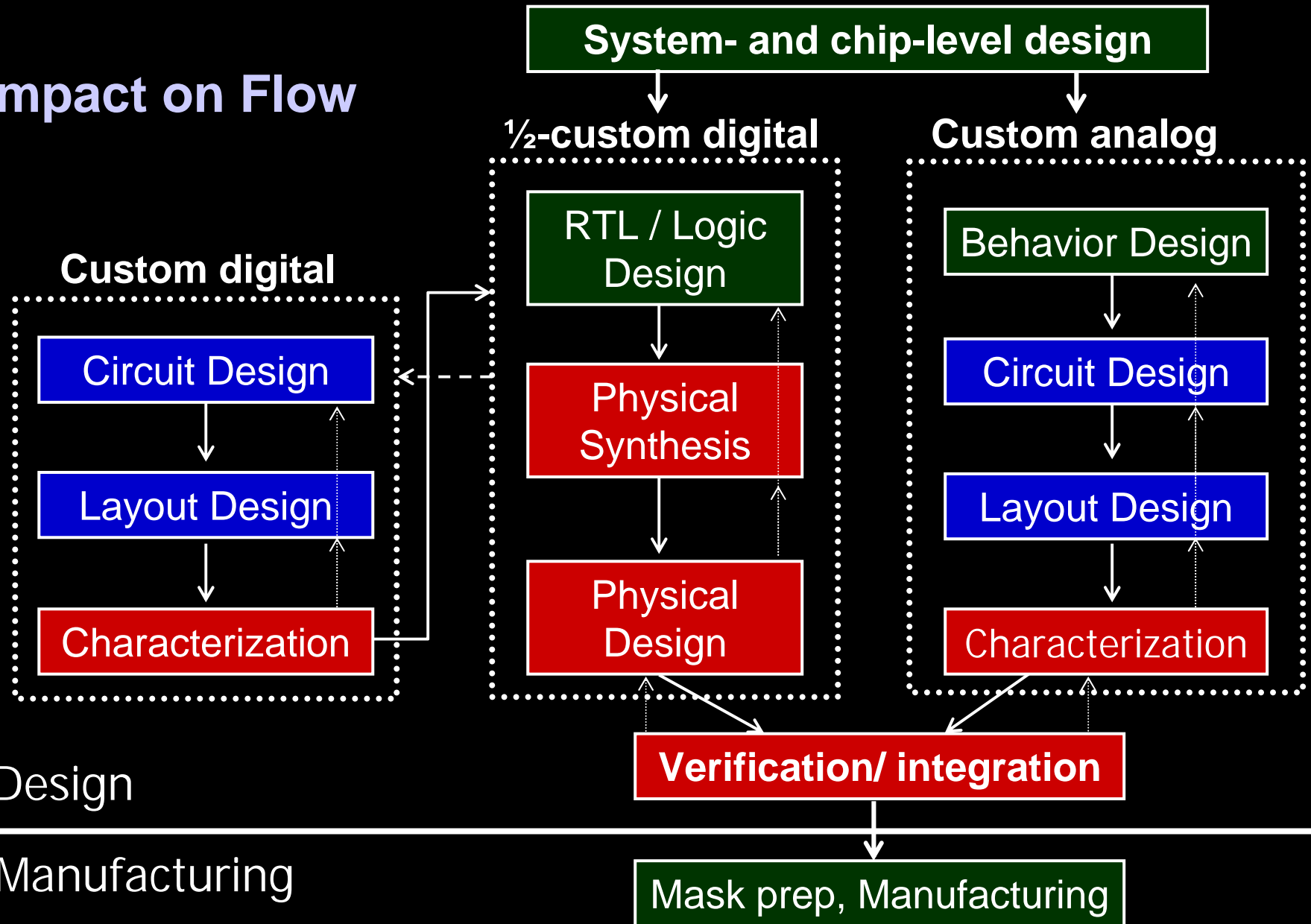
Supply and Ground Grid Noise & Electromigration

Electrical data	Physical data
Electrical data Specification Power Model Requirements	Geometrical data of supply nets
Timing data	Other
Variation in pin timing (delay, slew, setup, hold) from IR drop	Multiple supplies for analog blocks, multi Vt circuits, pads

Substrate Noise and Coupling

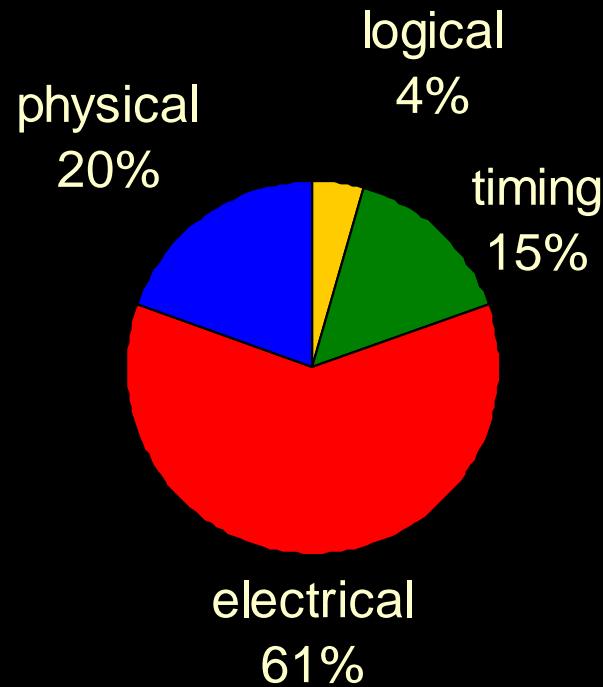
Electrical data	Physical data
Block-level impedance model	Regions
Noise sources, aggressor ports	Substrate access ports
Max noise for “victim” port	

Impact on Flow



An Electrical Phenomenon

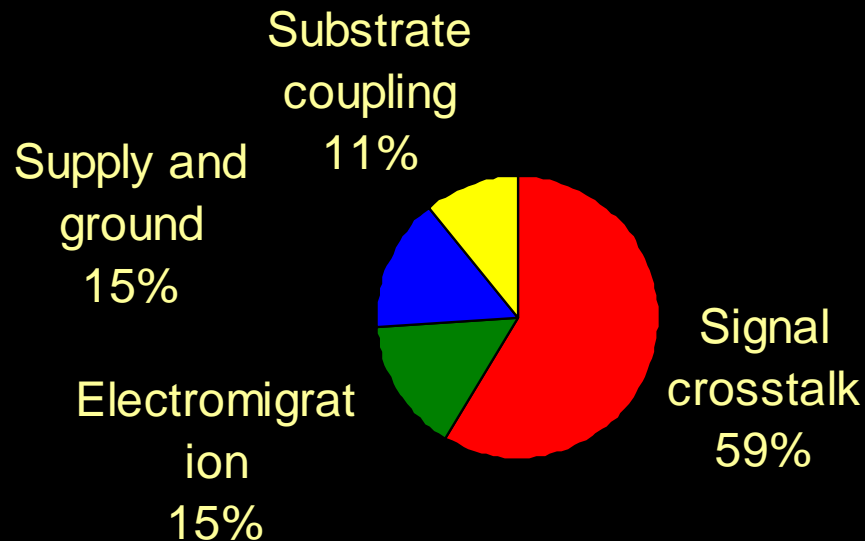
- **Types of SI SoC Task Deliverables**



Crosstalk A Key Concern

- **Types of SI SoC Task Deliverables**

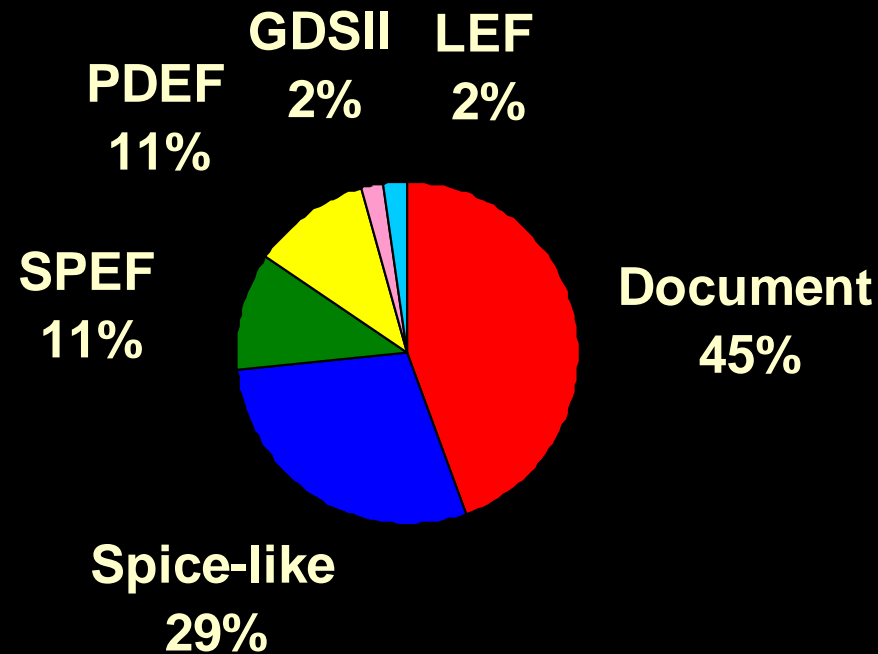
→ based on the SI phenomenon they address



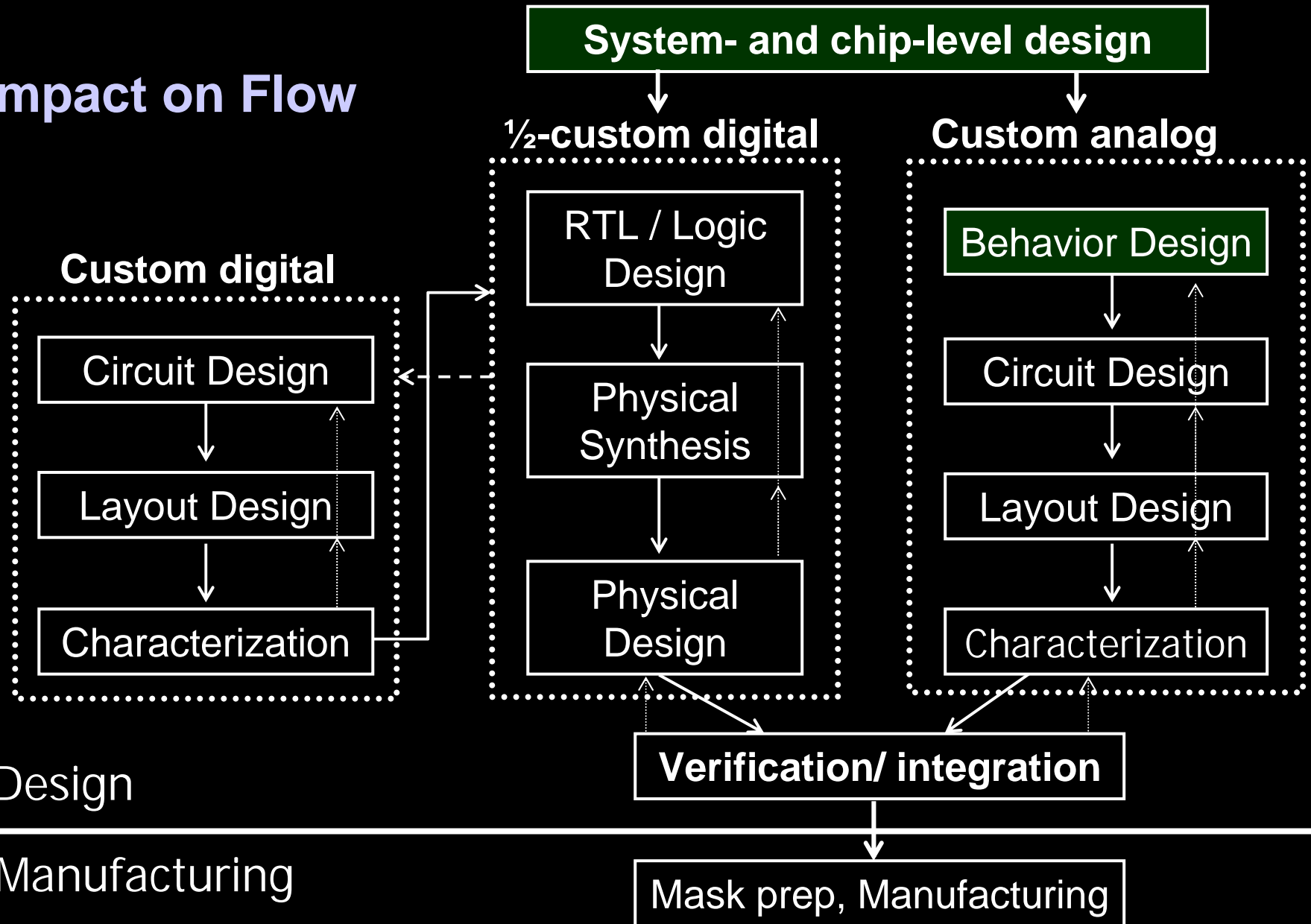
Standard Reuse in SoC Methodology

- **Formats/interfaces referred to in VSIA SI specification**

More than 50% existing standards



Impact on Flow



Design

Manufacturing

Impact on Early Design Exploration

- **Chip partitioning sub-flow**

- key for SoC

- Determines wiring = electrical SI

- Need to use standard SI block info

- **Analog-digital division line**

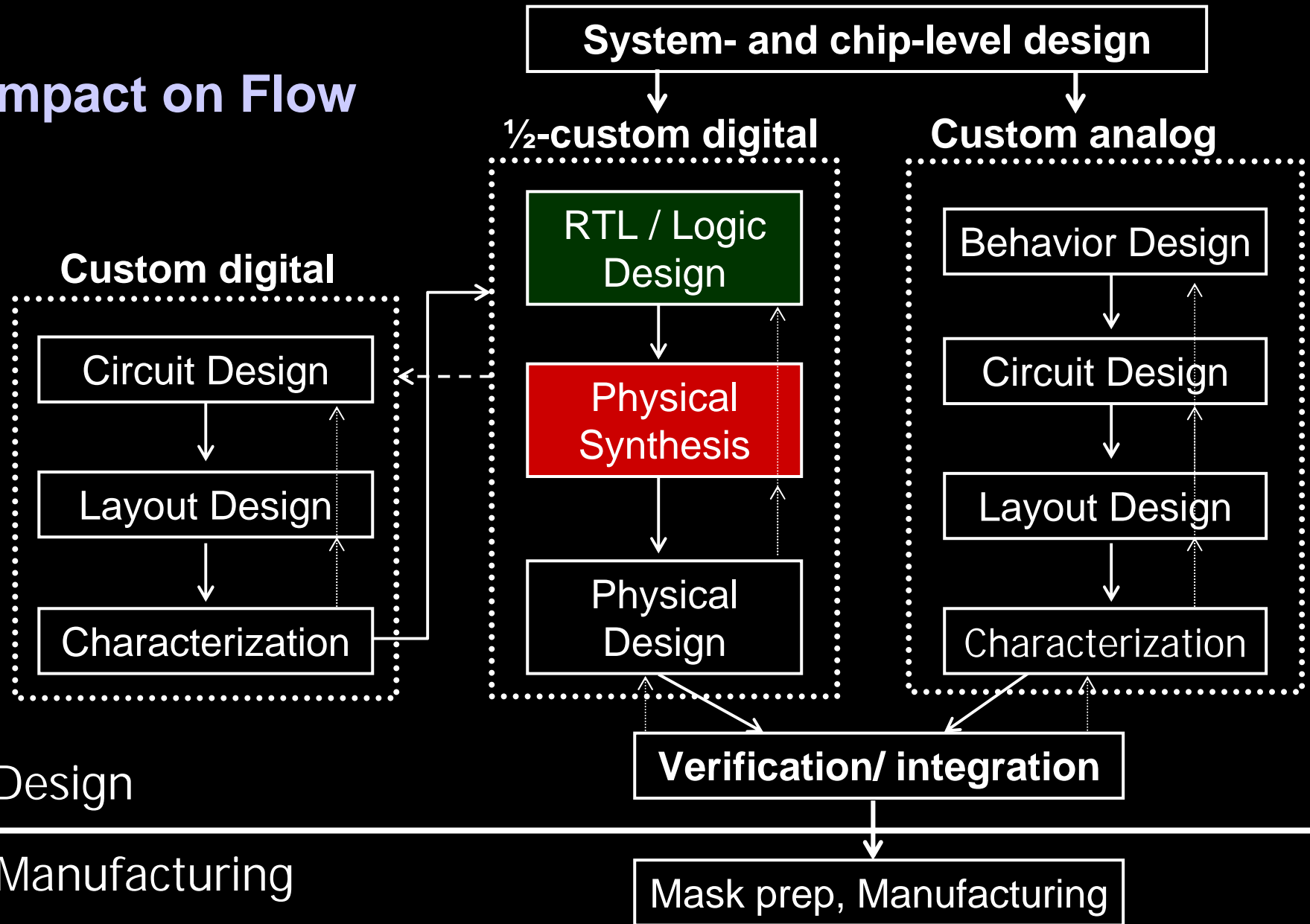
- fundamental in signal integrity management

- if actual spatial partitioning is done

- Functional division into A/D has strong influence on SI

- analog circuits tend to be more sensitive.

Impact on Flow



Impact on RTL / Logic Design

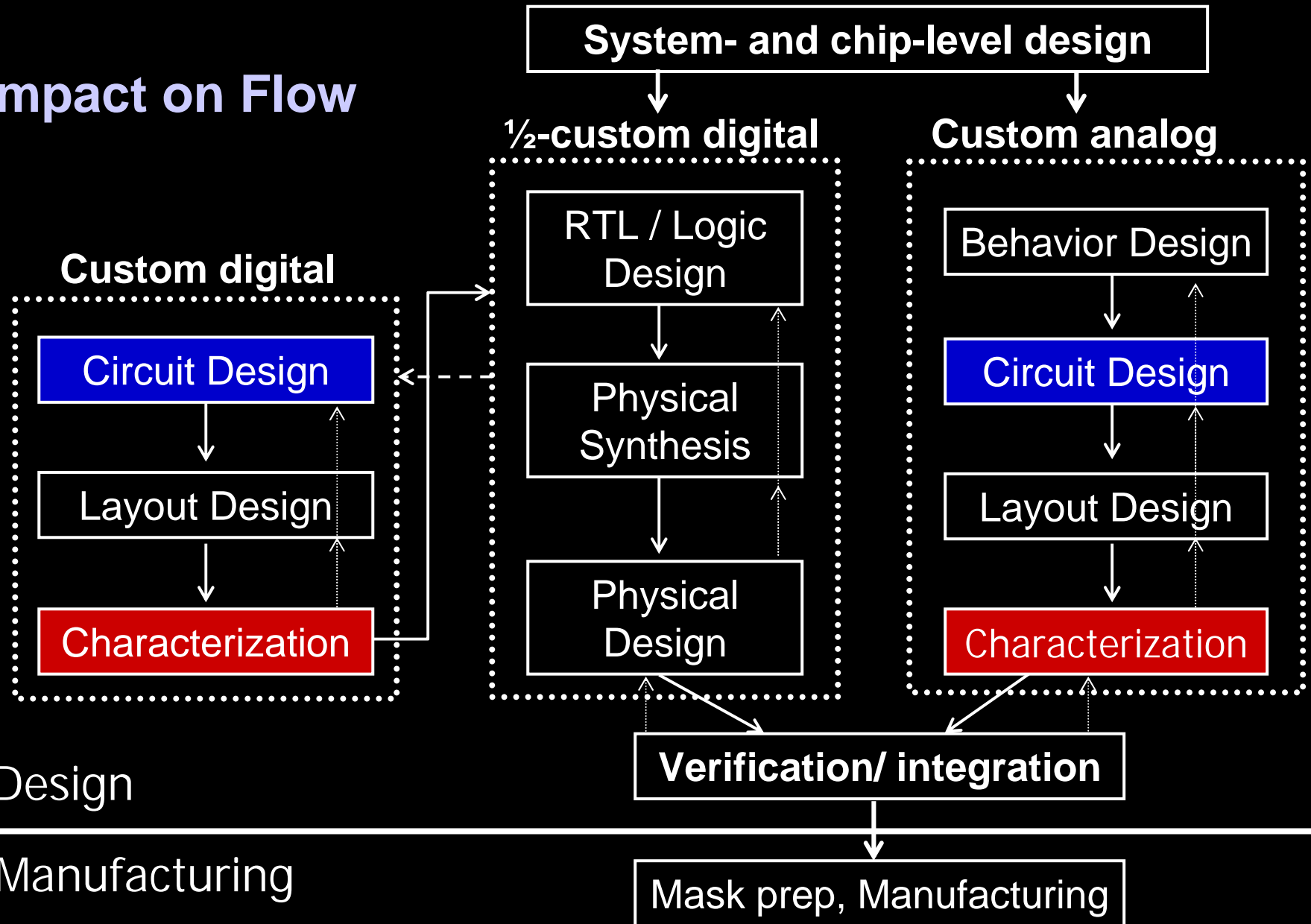
- **On synthesis**

- SI increases need to accommodate electrical effects
 - surge of SI effects near 100 nm
 - primary focus of SI embedding in the design flow

- **Example → crosstalk and supply noise**

- Strong influence on delay
 - Modern synthesis intimately related to timing
 - SI a primary factor to account for

Impact on Flow



Impact on Circuit Design

- **Impact of SI is obvious**

- SI is primarily a circuit-level phenomenon

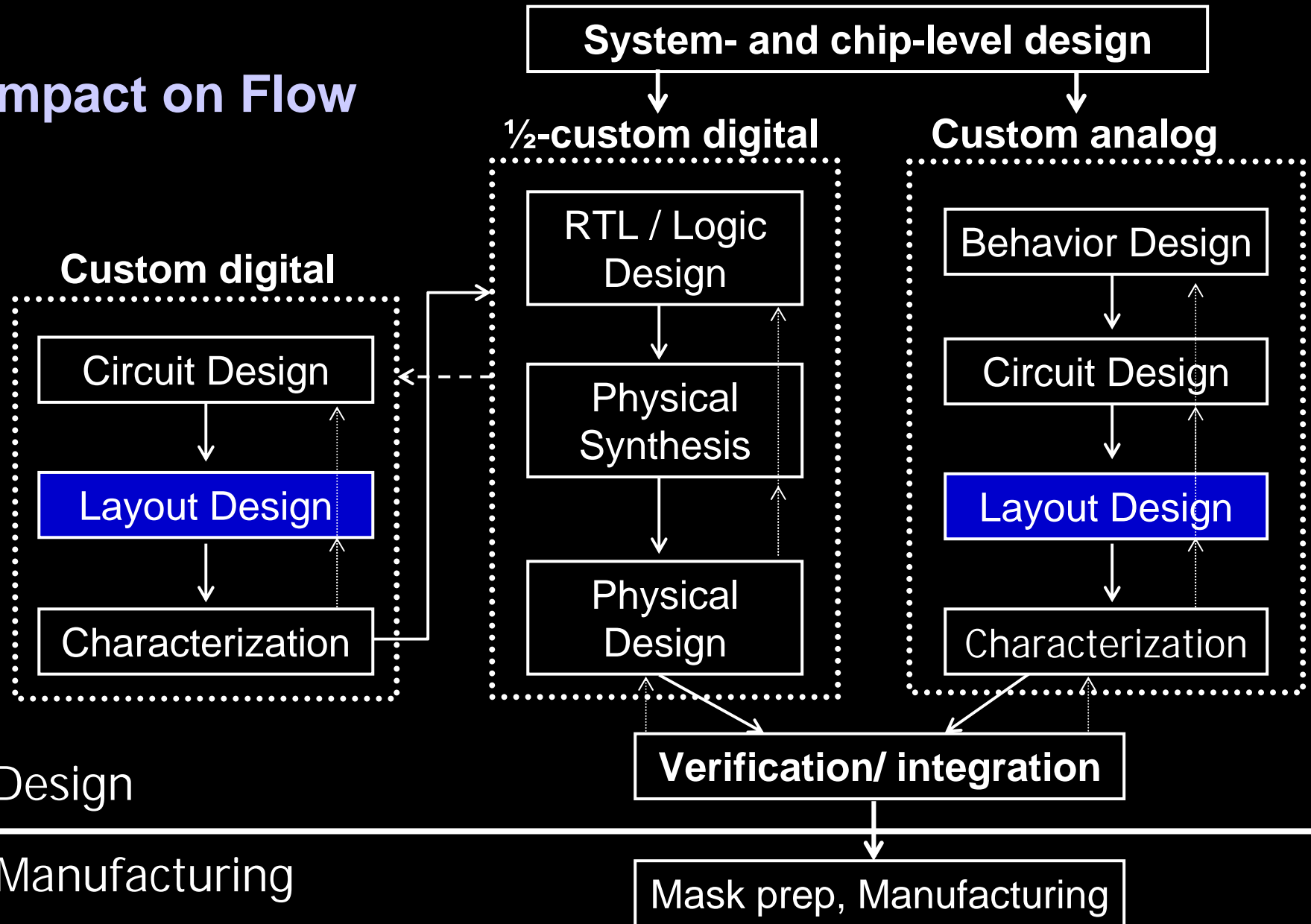
- Characterization fundamental flow path for SI info

- **Analog**

- Circuit topology and power increasingly important

- Raised in analog sub-flow of AMS design methodologies

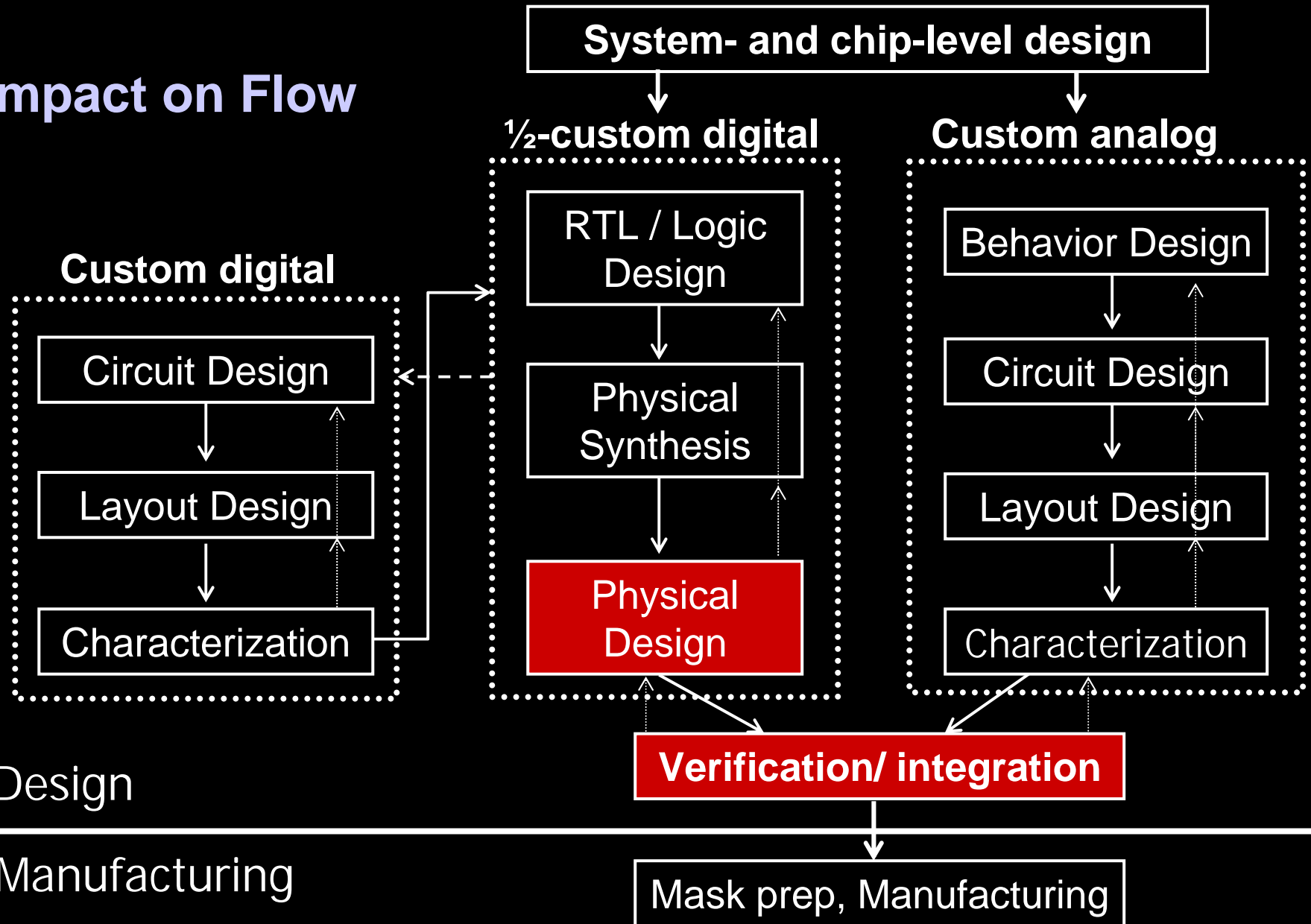
Impact on Flow



Impact on Layout Design

- **Most of the SI impact can be classified as**
embedding of isolation techniques in the design flow
Increasingly common in
 mixed-signal
 purely digital designs

Impact on Flow



Impact on Chip Integration

- **Renewed importance**

Due to rise of system-on-chip design

Key techniques

1. Floorplanning
2. Isolation

Conclusions

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Back-up Slides